


<b>Search Notes</b> 	<b>Application/Control No.</b> 10552088	<b>Applicant(s)/Patent Under Reexamination</b> YOON ET AL.
	<b>Examiner</b> TAI DUONG	<b>Art Unit</b> 2871

SEARCHED			
Class	Subclass	Date	Examiner
349	61, 65, 70, 1144	04/25/2009	TD
345	102	04/25/2009	TD
362	612, 613, 614	04/25/2009	TD

SEARCH NOTES			
Search Notes		Date	Examiner
EAST (US PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM TDB) see search history printout		04/25/2009	TD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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